

RELIABILITY REPORT



**RELIABILITY DATA
LM129 / LM329 / RH129**

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
HERMETIC TO-92	405	8338	0338	1,661.83	1
	394	8343	9524	1,764.73	0
	799			3,426.56	1

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
TO-92	277	9214	9524	393.54	0
	277			393.54	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP TO-220 TO-92	199	9233	9329	9.55	0
	50	9320	9320	2.40	0
	824	9214	0529	40.84	0
	1,073			52.79	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
HERMETIC TO-220 TO-92	279	8338	0338	23.40	0
	50	9320	9320	10.00	0
	290	9214	0529	29.00	0
	619			62.40	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
HERMETIC TO-92	212	8338	0338	7.01	0
	50	0325	0325	5.00	0
	262			12.01	0

(1) Assumes Activation Energy = 1.0 Electron Volts
 (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 1.18 FITS
 (3) Mean Time Between Failures in Years = 96,676
 (4) Assumes 20X Acceleration from 85°C to +131°C
 Note: 1 FIT = 1 Failure in One Billion Hours.